

IRF710B

400V N-Channel MOSFET

General Description

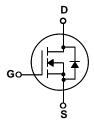
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies and electronic lamp ballasts based on half bridge.

Features

- 2.0A, 400V, $R_{DS(on)} = 3.4\Omega$ @V_{GS} = 10 V Low gate charge (typical 7.7 nC)
- Low Crss (typical 6.0 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		IRF710B	Units	
V_{DSS}	Drain-Source Voltage		400	V	
I _D	Drain Current - Continuous (T _C = 25°C)		2.0	А	
	- Continuous (T _C = 100°C)		1.3	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	6.0	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	100	mJ	
I _{AR}	Avalanche Current	(Note 1)	2.0	А	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	3.6	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.0	V/ns	
P _D	Power Dissipation (T _C = 25°C)		36	W	
	- Derate above 25°C		0.29	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.44	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	3	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		400			V
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced	to 25°C		0.4		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 400 V, V _{GS} = 0 V				10	μΑ
		V _{DS} = 320 V, T _C = 125°C	;			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 1.0 A			2.7	3.4	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 1.0 \text{ A}$	(Note 4)		2.2		S
C _{oss}	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz			6.0	40 8.0	pF pF
C _{rss}	' '	T = 1.0 MHZ				-	
Switchi	ng Characteristics						
t _{d(on)}	Turn-On Delay Time	V - 200 V I - 2 0 A			6.0	20	ns
t _r	Turn-On Rise Time	$V_{DD} = 200 \text{ V}, I_{D} = 2.0 \text{ A},$ $R_{G} = 25 \Omega$			25	60	ns
t _{d(off)}	Turn-Off Delay Time				20	50	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		25	60	ns
Qg	Total Gate Charge	V _{DS} = 320 V, I _D = 2.0 A,			7.7	10	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			1.5		nC
Q _{gd}	Gate-Drain Charge		(Note 4, 5)		3.2		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Rating	s				
I _S	Maximum Continuous Drain-Source Diode Forward Current				2.0	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				6.0	Α	
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.0 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 2.0 \text{ A},$			210		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)			0.9		μС

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 44mH, I_{AB} = 2.0A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
 3. I_{SD} ≤ 2.0A, di/dt \geq 200A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C
 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2%
 5. Essentially independent of operating temperature

Typical Characteristics

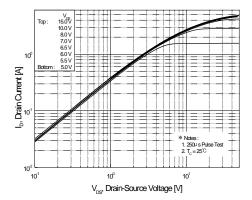


Figure 1. On-Region Characteristics

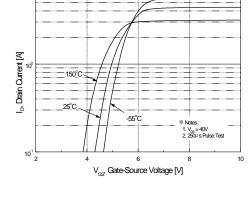


Figure 2. Transfer Characteristics

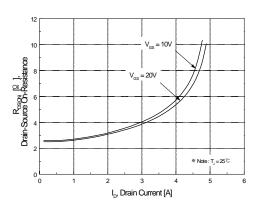


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

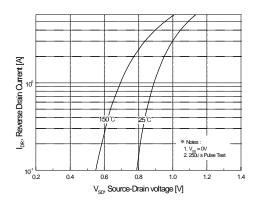


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

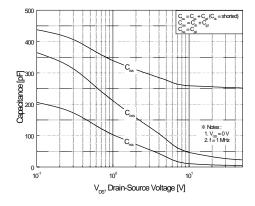


Figure 5. Capacitance Characteristics

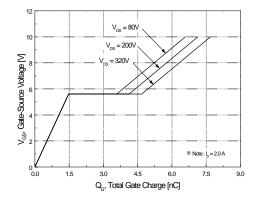


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

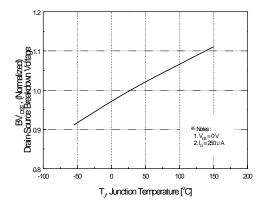
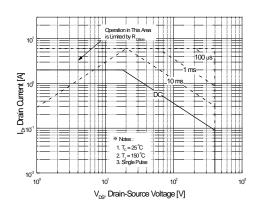


Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



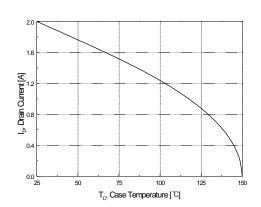


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

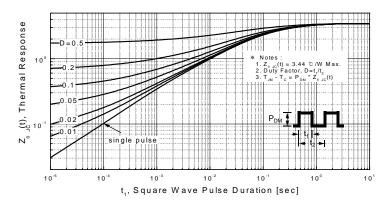
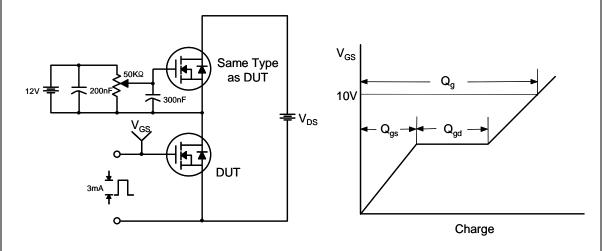


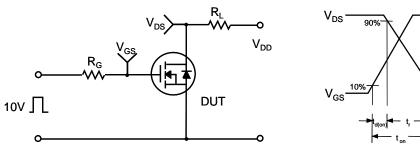
Figure 11. Transient Thermal Response Curve

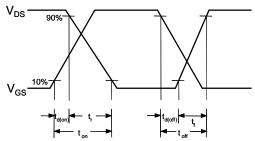
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Gate Charge Test Circuit & Waveform

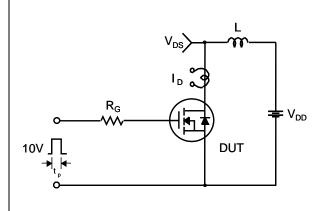


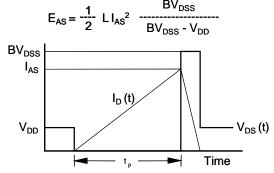
Resistive Switching Test Circuit & Waveforms



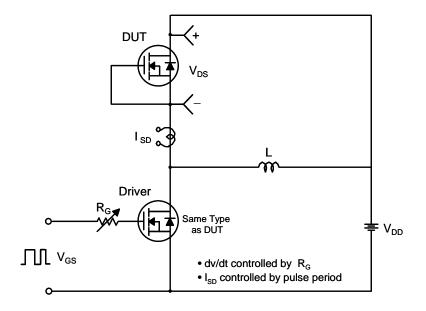


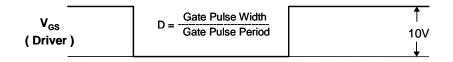
Unclamped Inductive Switching Test Circuit & Waveforms

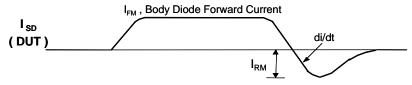




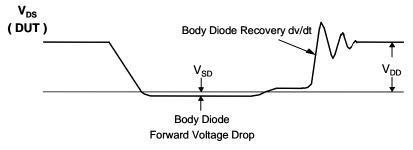
Peak Diode Recovery dv/dt Test Circuit & Waveforms

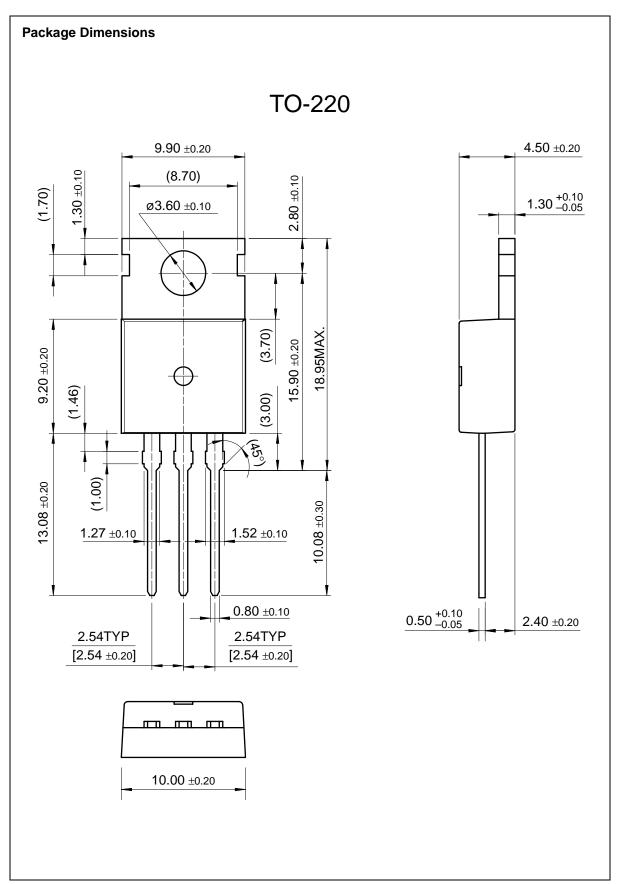






Body Diode Reverse Current





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